

Aaeon Technology (Europe) B.V.

# EP-SSM242256AA1 M.2 2242 SATA SSD 256GB 3D TLC Specification

## **Version 1.1**



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# **Revision History**

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1.1	2016/05/26	Update performance, TBW and power consumption Update chapter 6 supported command	Lisa Wu
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# **Product Overview**

- Capacity
  - 256 GB
- Form Factor
  - M.2 2242-D5-B-M
- SATA Interface
  - SATA Revision 3.2
  - SATA 1.5Gbps, 3Gbps, and 6Gbps interface
- Flash Interface
  - Flash type: TLC
  - 1pcs to 2pcs of BGA/TSOP flash
- Performance
  - Read: 550 MB/s
  - Write: 500 MB/s
- Power Consumption<sup>Note1</sup>
  - Active mode: < 1,450 mW
  - Idle mode: < 215 mW</p>
  - DEVSLP mode: < 4.9 mW

- MTBF
  - More than 2,000,000 hours
- Advanced Flash Management
  - Static and Dynamic Wear Leveling
  - Bad Block Management
  - TRIM
  - SMART
  - Over-Provision
  - Firmware Update
  - SmartZIP<sup>TM</sup>
- Low Power Management
  - DEVSLP Mode (Optional)
  - DIPM/HIPM Mode
- Temperature Range
  - Operation: 0°C ~ 70°C
  - Storage: -40°C ~ 85°C
- RoHS compliant

#### Notes:

1. Please see "4.2 Power Consumption" for details.



# **Performance and Power Consumption**

		Performance				Power Consumption		
Canacity	Flash Structure	CrystalDiskMark		ATTO		Dood	\A/#i+o	DEVELD
Capacity	Flash Structure	Read	Write	Read	Write	Read (mW)	Write (mW)	DEVSLP (mW)
		(MB/s)	(MB/s)	(MB/s)	(MB/s)	(IIIVV)	(IIIVV)	(IIIVV)
256GB	128GBx2, BGA, TSB Bics4	550	500	560	540	1,400	1,450	4.9

## NOTE:

For more details on Power Consumption, please refer to Chapter 4.2.



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## 1. INTRODUCTION

## 1.1. General Description

Phison's PS3111 M.2 2242 delivers all the advantages of flash disk technology with the Serial ATA I/II/III interface and is fully compliant with the standard Next Generation Form Factor (NGFF) called M.2 Card Format, which is generated by Intel. The PS3111 M.2 2242 is designed to operate at a maximum operating frequency of 200MHz with 30MHz external crystal. Its capacity could provide a wide range up to 512GB. The power consumption of the M.2 2242 is much lower than traditional hard drives, making it the best

## 1.2. Controller Block Diagram

embedded solution for new platforms.

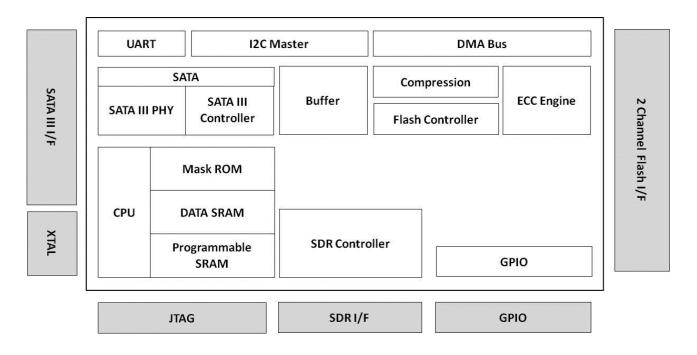


Figure 1-1 PS3111 M.2 2242 Controller Block Diagram



## 1.3. Product Block Diagram

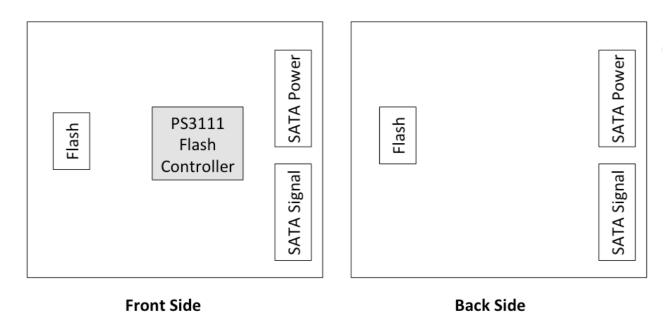


Figure 1-2 PS3111 M.2 2242 Product Block Diagram

## 1.4. Flash Management

## 1.4.1. Error Correction Code (ECC)

Flash memory cells will deteriorate with use, which might generate random bit errors in the stored data. Thus, PS3111 M.2 2242 applies the LDPC (Low Density Parity Check) of ECC algorithm, which can detect and correct errors occur during read process, ensure data been read correctly, as well as protect data from corruption.

#### 1.4.2. Wear Leveling

NAND flash devices can only undergo a limited number of program/erase cycles, and in most cases, the flash media are not used evenly. If some areas get updated more frequently than others, the lifetime of the device would be reduced significantly. Thus, Wear Leveling is applied to extend the lifespan of NAND flash by evenly distributing write and erase cycles across the media.

Phison provides advanced Wear Leveling algorithm, which can efficiently spread out the flash usage through the whole flash media area. Moreover, by implementing both dynamic and static Wear Leveling algorithms, the life expectancy of the NAND flash is greatly improved.



#### 1.4.3. Bad Block Management

Bad blocks are blocks that include one or more invalid bits, and their reliability is not guaranteed. Blocks that are identified and marked as bad by the manufacturer are referred to as "Initial Bad Blocks". Bad blocks that are developed during the lifespan of the flash are named "Later Bad Blocks". Phison implements an efficient bad block management algorithm to detect the factory-produced bad blocks and manages any bad blocks that appear with use. This practice further prevents data being stored into bad blocks and improves the data reliability.

#### 1.4.4. TRIM

TRIM is a feature which helps improve the read/write performance and speed of solid-state drives (SSD). Unlike hard disk drives (HDD), SSDs are not able to overwrite existing data, so the available space gradually becomes smaller with each use. With the TRIM command, the operating system can inform the SSD which blocks of data are no longer in use and can be removed permanently. Thus, the SSD will perform the erase action, which prevents unused data from occupying blocks all the time.

#### 1.4.5. SMART

SMART, an acronym for Self-Monitoring, Analysis and Reporting Technology, is an open standard that allows a hard disk drive to automatically detect its health and report potential failures. When a failure is recorded by SMART, users can choose to replace the drive to prevent unexpected outage or data loss. Moreover, SMART can inform users of impending failures while there is still time to perform proactive actions, such as copy data to another device.

#### 1.4.6. Over-Provision

Over Provisioning refers to the inclusion of extra NAND capacity in a SSD, which is not visible and cannot be used by users. With Over Provisioning, the performance and IOPS (Input/Output Operations per Second) are improved by providing the controller additional space to manage P/E cycles, which enhances the reliability and endurance as well. Moreover, the write amplification of the SSD becomes lower when the controller writes data to the flash.



#### 1.4.7. Firmware Upgrade

Firmware can be considered as a set of instructions on how the device communicates with the host. Firmware will be upgraded when new features are added, compatibility issues are fixed, or read/write performance gets improved.

## 1.5. Low Power Management

#### 1.5.1. DEVSLP Mode (Optional)

With the increasing need of aggressive power/battery life, SATA interfaces include a new feature, Device Sleep (DEVSLP) mode, which helps further reduce the power consumption of the device. DEVSLP enables the device to completely power down the device PHY and other sub-systems, making the device reach a new level of lower power operation. The DEVSLP does not specify the exact power level a device can achieve in the DEVSLP mode, but the power usage can be dropped down to 5mW or less.

#### 1.5.2. DIPM/HIPM Mode

SATA interfaces contain two low power management states for power saving: Partial and Slumber modes. For Partial mode, the device has to resume to full operation within 10 microseconds, whereas the device will spend 10 milliseconds to become fully operational in the Slumber mode. SATA interfaces allow low power modes to be initiated by Host (HIPM, Host Initiated Power Management) or Device (DIPM, Device Initiated Power Management). As for HIPM, Partial or Slumber mode can be invoked directly by the software. For DIPM, the device will send requests to enter Partial or Slumber mode.

## 1.6. Power Loss Protection: Flushing Mechanism

Power Loss Protection is a mechanism to prevent data loss during unexpected power failure. DRAM is a volatile memory and frequently used as temporary cache or buffer between the controller and the NAND flash to improve the SSD performance. However, one major concern of the DRAM is that it is not able to keep data during power failure. Accordingly, the PS3111 applies the *GuaranteedFlush* technology, which requests the controller to transfer data to the cache. For PS3111, SDR performs as a cache, and its size is



32MB. Only when the data is fully committed to the NAND flash will the controller send acknowledgement (ACK) to the host. Such implementation can prevent false-positive performance and the risk of power cycling issues.

Additionally, it is critical for a controller to shorten the time the in-flight data stays in the cache. Thus, Phison's PS3111 applies an algorithm to reduce the amount of data resides in the cache to provide a better performance. This *SmartCacheFlush* technology allows incoming data to only have a "pit stop" in the cache and then move to the NAND flash at once. If the flash is jammed due to particular file sizes (such as random 4KB data), the cache will be treated as an "organizer", consolidating incoming data into groups before written into the flash to improve write amplification.

In sum, with Flush Mechanism, PS3111 proves to provide the reliability required by consumer, industrial, and enterprise-level applications.

## 1.7. Advanced Device Security Features

#### 1.7.1. Secure Erase

Secure Erase is a standard ATA command and will write all "0x00" to fully wipe all the data on hard drives and SSDs. When this command is issued, the SSD controller will erase its storage blocks and return to its factory default settings.

#### 1.7.2. Write Protect

When a SSD contains too many bad blocks and data are continuously written in, then the SSD might not be usable anymore. Thus, Write Protect is a mechanism to prevent data from being written in and protect the accuracy of data that are already stored in the SSD.

## 1.8. SSD Lifetime Management

#### 1.8.1. Thermal Monitor (Optional)

Thermal monitors are devices for measuring temperature, and can be found in SSDs in order to issue warnings when SSDs go beyond a certain temperature. The higher temperature the thermal monitor detects, the more power the SSD consumes, causing the SSD to get aging quickly. Hence, the processing speed of a SSD should be under control to prevent temperature from exceeding a certain range. Meanwhile, the SSD can achieve power savings.



## 1.9. An Adaptive Approach to Performance Tuning

## 1.9.1. Throughput

Based on the available space of the disk, PS3111 will regulate the read/write speed and manage the performance of throughput. When there still remains a lot of space, the firmware will continuously perform read/write action. There is still no need to implement garbage collection to allocate and release memory, which will accelerate the read/write processing to improve the performance. Contrarily, when the space is going to be used up, PS3111 will slow down the read/write processing, and implement garbage collection to release memory. Hence, read/write performance will become slower.

#### 1.9.2. Predict & Fetch

Normally, when the host tries to read data from the SSD, the SSD will only perform one read action after receiving one command. However, PS3111 applies *Predict & Fetch* to improve the read speed. When the host issues sequential read commands to the SSD, the SSD will automatically expect that the following will also be read commands. Thus, before receiving the next command, flash has already prepared the data. Accordingly, this accelerates the data processing time, and the host does not need to wait so long to receive data.

## 1.9.3.SmartZIP™

Write data to the NAND Flash costs time. To improve the write speed performance, PS3111 launches with compression technique-- SmartZIP<sup>TM</sup>.

Whether a file could be compressed or not depending on the file type, for file types have redundancy data pattern, through our embedded encode engine, we could reduce the amount of data that is actually written to the Flash. Comparing to the SSD without the compression, write efficiency is raised and the SSD endurance is also improved since Flash could be benefit from less data written for a longer SSD lifetime.



## 2. PRODUCT SPECIFICATIONS

- Capacity
  - From 30/32GB up to 480/512GB (support 48-bit addressing mode)
- Electrical/Physical Interface
  - SATA Interface
    - ♦ Compliant with SATA Revision 3.2
    - ♦ Compatible with SATA 1.5Gbps, 3Gbps and 6Gbps interface
    - Support power management
    - ♦ Support expanded register for SATA protocol 48 bits addressing mode
    - ♦ Embedded BIST function for SATA PHY for low cost mass production
- Built-in 2-channel NAND flash interface controller
  - Compliant with Toggle 1.0 and Toggle 2.0 NAND Flash interface
  - Compliant with ONFI 4.0 interface:
    - ♦ SDR up to mode 5
    - ♦ NV-DDR up to mode 5
    - ♦ NV-DDR2 up to mode 7
    - ♦ NV-DDR3 up to mode 8

#### Supported NAND Flash

- Support up to 16 Flash Chip Enables (CE) within single design
- Toshiba 24nm SLC; 15nm/3D-NAND MLC; 15nm/3D-NAND TLC
- Intel/Micron 16nm/3D-NAND MLC and TLC
- Hynix 16nm/3D-NAND
- Support all types of SLC/MLC/TLC/3D-NAND, 8KB/page and 16K/page NAND flash
- Support ONFI 2.3, ONFI 3.0, ONFI 3.2 and ONFI 4.0 interface: 2 channels at maximum
- Support 8-bit I/O NAND Flash
- Contain 1pcs to 2pcs of BGA flash
- ECC Scheme
  - PS3111 M.2 2242 applies the LDPC (Low Density Parity Check) of ECC algorithm.
- UART function
- GPIO
- Support SMART and TRIM commands



#### Performance

			Seque	ntial
Capacity	Flash Structure	Flash Type	Read	Write
			(MB/s)	(MB/s)
120/128GB	128GBx2	BGA, TSB Bics4	550	450

#### **NOTES:**

- 1. The performance was measured using CrystalDiskMarkv5.0x64 with SATA 6Gbps host.
- 2. Samples were built using Toshiba 15nm, Toshiba Bics2, Bics3 and Micron BOKB TLC.
- 3. Performance may differ according to flash configuration and platform.
- 4. The table above is for reference only. The criteria for MP (mass production) and for accepting goods shall be discussed based on different flash configuration.



# 3. ENVIRONMENTAL SPECIFICATIONS

## 3.1. Environmental Conditions

## 3.1.1. Temperature and Humidity

Temperature:

♦ Storage: -40°C to 85°C♦ Operational: 0°C to 70°C

• Humidity: RH 90% under 40°C (operational)

**Table 3-1 High Temperature Test Condition** 

	Temperature	Humidity	Test Time
Operation	70°C	0% RH	72 hours
Storage	85°C	0% RH	72 hours

**Result:** No any abnormality is detected.

**Table 3-2 Low Temperature Test Condition** 

	Temperature	Humidity	Test Time
Operation	0°C	0% RH	72 hours
Storage	-40°C	0% RH	72 hours

**Result:** No any abnormality is detected.

**Table 3-3 High Humidity Test Condition** 

	Temperature	Humidity	Test Time
Operation	40°C	90% RH	4 hours
Storage	40°C	93% RH	72 hours

**Result:** No any abnormality is detected.

**Table 3-4 Temperature Cycle Test** 

	Temperature	Test Time	Cycle
Operation	0°C	30 min	10 Cycles
Operation	70°C	30 min	10 Cycles
Storage	-40°C	30 min	10 Cycles
	85°C	30 min	To Cycles

**Result:** No any abnormality is detected.



#### 3.1.2.Shock

Table 3-5 PS3111 M.2 2242 Shock Specification

	Acceleration Force	Half Sin Pulse Duration
Non-operational	1500G	0.5ms

Result: No any abnormality is detected when power on.

#### 3.1.3. Vibration

Table 3-6 PS3111 M.2 2242 Vibration Specification

	Condition		
	Frequency/Displacement	Frequency/Acceleration	
Non-operational	20Hz~80Hz/1.52mm	80Hz~2000Hz/20G	X, Y, Z axis/60 min for each

**Result:** No any abnormality is detected when power on.

## 3.1.4. Drop

Table 3-7 PS3111 M.2 2242 Drop Specification

	Height of Drop	Number of Drop
Non-operational	80cm free fall	6 face of each unit

**Result:** No any abnormality is detected when power on.

#### **3.1.5. Bending**

Table 3-8 PS3111 M.2 2242 Bending Specification

	Force	Action
Non-operational	≥ 20N	Hold 1min/5times

**Result:** No any abnormality is detected when power on.

## **3.1.6.** Torque

Table 3-9 PS3111 M.2 2242 Torque Specification

	Force	Action
Non-operational	0.5N-m or ±2.5 deg	Hold 1min/5times

**Result:** No any abnormality is detected when power on.



## 3.1.7. Electrostatic Discharge (ESD)

Table 3-10 PS3111 M.2 2242 Contact ESD Specification

Device	Capacity	Temperature	Relative Humidity	+/- 4KV	Result
				Device functions are affected,	
M.2 2242	256GB 24.0°C	24.0%	400/ (DLI)	but EUT will be back to its	DACC
		49% (RH)	normal or operational state	PASS	
				automatically.	

## 3.1.8. EMI Compliance

FCC: CISPR22 / CISPR32CE: EN55022 / EN55032

BSMI 13438

#### 3.2. MTBF

MTBF, an acronym for Mean Time Between Failures, is a measure of a device's reliability. Its value represents the average time between a repair and the next failure. The measure is typically in units of hours. The higher the MTBF value, the higher the reliability of the device. The predicted result of Phison's PS3111 M.2 2242 is more than 2,000,000 hours.

## 3.3. Certification & Compliance

- RoHS
- SATA III (SATA Rev. 3.2)
- Up to ATA/ATAPI-8 (Including S.M.A.R.T)



# 4. ELECTRICAL SPECIFICATIONS

## 4.1. Supply Voltage

Table 4-1 Supply Voltage of PS3111 M.2 2242

Parameter	Rating
Operating Voltage	3.3V

## 4.2. Power Consumption

#### Table 4-2 Power Consumption of PS3111 M.2 2242

Capacity	Flash Structure	Flash Type	Read	Write	Partial	Slumber	Idle	DEVSLP
60/64GB	128GB x 2	BGA, TSB Bics4	1,400	1,450	16	12	215	4.9

Unit: mW

#### **NOTES:**

- 1. The average value of power consumption is achieved based on 100% conversion efficiency.
- 2. The measured power voltage is 3.3V.
- 3. Samples were built using Toshiba 15nm, Toshiba Bics2, Bics3 and Micron BOKB TLC NAND. It's measured under ambient temperature.
- 4. Sequential R/W is measured while testing 4000MB sequential R/W 5 times by CyrstalDiskMark. DEVSLP is measured while entering device sleep mode for 5 minutes.
- 5. Power Consumption may differ according to flash configuration and platform.



# **5.1.** Pin Assignment and Descriptions

Table 5-1 defines the signal assignment of the internal NGFF connector for SSD usage, described in the PCI Express M.2 Specification version 1.0 of the PCI-SIG.

Table 5-1 Pin Assignment and Description of PS3111 M.2 2242

Pin #	SATA Pin	Description
1	CONFIG_3	Ground
2	3.3V	Supply pin
3	GND	Ground
4	3.3V	Supply pin
5	N/C	No Connect
6	N/C	No Connect
7	N/C	No Connect
8	N/C	No Connect
9	N/C or GND Note	No Connect or Ground
		Status indicators via LED devices that will be provided by the
10	DAS/DSS# (O) (OD)	system Active Low. A pulled-up LED with series current
		limiting resistor should allow for 9mA when On.
11	N/C	No Connect
12	Module Key	
13	Module Key	
14	Module Key	
15	Module Key	
16	Module Key	
17	Module Key	
18	Module Key	
19	Module Key	
20	N/C	No Connect
21	CONFIG_0	Ground
22	N/C	No Connect
23	N/C	No Connect
24	N/C	No Connect
25	N/C	No Connect
26	N/C	No Connect
27	GND	Ground
28	N/C	No Connect



Pin #	SATA Pin	Description			
29	N/C	No Connect			
30	N/C	No Connect			
31	N/C	No Connect			
32	N/C	No Connect			
33	GND	Ground			
34	N/C	No Connect			
35	N/C	No Connect			
36	N/C	No Connect			
37	N/C	No Connect			
		Device Sleep, Input.			
38	DEVSLP (I) (0/3.3V)	When driven high the host is informing the SSD to enter a			
		low power state			
39	GND	Ground			
40	N/C	No Connect			
41	SATA-B+	SATA differential signals in the SATA specification			
42	N/C	No Connect			
43	SATA-B-	SATA differential signals in the SATA specification			
44	N/C	No Connect			
45	GND	Ground			
46	N/C	No Connect			
47	SATA-A-	SATA differential signals			
47	SATA-A-	in the SATA specification			
48	N/C	No Connect			
49	SATA-A+	SATA differential signals			
43	SATATAT	in the SATA specification			
50	N/C	No Connect			
51	GND	Ground			
52	N/C	No Connect			
53	N/C	No Connect			
54	N/C	No Connect			
55	N/C	No Connect			
56	Reserved for MFG	No Connect			
	Data	No connect			
57	GND	Ground			
58	Reserved for MFG	No Connect			
	Clock	110 comice			
59	Module Key				
60	Module Key				



Pin #	SATA Pin	Description
61	Module Key	
62	Module Key	
63	Module Key	
64	Module Key	
65	Module Key	
66	Module Key	
67	N/C	No Connect
68	SUSCLK (I) (0/3.3V)	No Connect
69	CONFIG_1	Ground
70	3.3V	Supply pin
71	GND	Ground
72	3.3V	Supply pin
73	GND	Ground
74	3.3V	Supply pin
75	CONFIG_2	Ground

NOTE: N/C for Socket 2 and GND for Socket 3.



# **6. SUPPORTED COMMANDS**

## **6.1. ATA Command List**

The following ATA command list table is followed by ATA8-ACS4 SPEC.

**Table 6-1 ATA Command List** 

Op Code	Description		Op Co	de	Description
00h	NOP	C9h			Read DMA without Retry
06h	Data Set Management	CAh			Write DMA
10h-1Fh	Recalibrate		CBh		Write DMA without Retry
20h	Read Sectors		CEh		Write Multiple FUA EXT
21h	Read Sectors without Retry		E0h		Standby Immediate
24h	Read Sectors EXT		E1h		Idle Immediate
25h	Read DMA EXT		E2h		Standby
27h	Read Native Max Address EXT		E3h		Idle
29h	Read Multiple EXT		E4h		Read Buffer
2Fh	Read Log EXT		E5h		Check Power Mode
30h	Write Sectors		E6h		Sleep
31h	Write Sectors without Retry		E7h		Flush Cache
34h	Write Sectors EXT		E8h		Write Buffer
35h	Write DMA EXT		E9h		READ BUFFER DMA
37h	Set Native Max Address EXT		EAh		Flush Cache EXT
38h	CFA Write Sectors Without Erase		EBh		Write Buffer DMA
39h	Write Multiple EXT		ECh		Identify Device
3Dh	Write DMA FUA EXT		EFh		Set Features
3Fh	Write Long EXT	EFh	02	h	Enable volatile writ
40h	Read Verify Sectors	EFh	03	h	Set transfer mode
41h	Read Verify Sectors without Retry	EFh	05	h	Enable the APM feature set
42h	Read Verify Sectors EXT	EFh	10	h	Enable use of SATA
44h	Zero EXT	EFh	10h	02h	Enable DMA Setup FIS Auto-Activate optimization
45h	Write Uncorrectable EXT	EFh	10h	03h	Enable Device-initiated interface power state (DIPM) transitions
47h	Read Log DMA EXT	EFh	10h	06h	Enable Software Settings Preservation (SSP)
	Write Log DMA EXT	10h 07h		07h	Enable Device Automatic Partial to
57h 60h	Pood EDDMA Quousd	EFh	106	004	Slumber transitions
	Read FPDMA Queued	EFh	10h	09h	Enable Device Sleep
61h	Write FPDMA Queued	EFh	55	h	Disable read look-a
70h-7Fh	Seek	EFh	66	h	Disable reverting to power-on defaults



Op Code		Description	0	Op Code		Description
9	0h	Execute Device Diagnostic	EFh	EFh 82h		Disable volatile write cache
9	1h	Initialize Device Parameters	EFh 85h		5h	Disable the APM feature set
9	2h	Download Microcode	EFh	90	)h	Disable use of SATA feature set
9:	3h	Download Microcode DMA	EFh	90h	02h	Disable DMA Setup FIS Auto-Activate optimization
В	0h	SMART	EFh	90h	03h	Disable Device-initiated interface power state (DIPM) transitions
B0h	D0h	SMART READ DATA	EFh	90h	06h	Disable Software Settings Preservation (SSP)
B0h	D1h	SMART READ ATTRIBUTE THRESHOLDS	EFh	EFh 90h 07h		Disable Device Automatic Partial to Slumber transitions
B0h	D2h	SMART ENABLE/DISABILE ATTRIBUTE AUTOSAVE	EFh	90h	09h	Disable Device Sleep
B0h	D3h	SMART SAVE ATTRIBUTE VALUES	EFh	AA	۸h	Enable read look-ahead
B0h	D4h	SMART EXECUTE OFF-LINE IMMEDIATE	EFh	CC	Ch	Enable reverting to power-on defaults
B0h	D5h	SMART READ LOG		F1h		Security Set Password
B0h	D6h	SMART WRITE LOG		F2h		Security Unlock
B0h	D8h	SMART ENABLE OPERATIONS		F3h		Security Erase Prepare
B0h	D9h	SMART DISABLE OPERATIONS		F4h		Security Erase Unit
B0h	DAh	SMART RETURN STATUS		F5h		Security Freeze Lock
B0h	DBh	SMART ENABLE/DISABILE AUTOMATIC OFF-LINE	F6h			Security Disable Password
B1h		Device Configuration		F8h		Read Native Max Address
B4h Sanitize		Sanitize		F9h		Set Max Address
C	C4h Read Multiple F9h 01h		SET MAX SET PASSWORD			
C	C5h Write Multiple F9h 02h		2h	SET MAXLOCK		
С	6h	Set Multiple Mode	F9h 03h		 3h	SET MAX UNLOCK
С	8h	Read DMA	F9h	04	1h	SET MAX FREEZE LOCIK



# **6.2. Identify Device Data**

The following table details the sector data returned by the IDENTIFY DEVICE command of ATA8-ACS4 SPEC.

**Table 6-2 List of Device Identification** 

	F: Fixed			
	V: Variable			
Word	V. Variable X:	Default Value	Description	
word	retired/obsolete	Delault Value	Description	
	/reserved	00401		
0	F	0040h	General configuration bit-significant information	
1	Х	*1	Obsolete	
2	F	C837h	Specific configuration	
3	X	0010h	Obsolete	
4-5	X	00000000h	Retired	
6	X	003Fh	Obsolete	
7-8	Х	00000000h	Reserved for assignment by the Compact Flash	
			Association	
9	X	0000h	Retired	
10-19	V	Varies	Serial number (20 ASCII characters)	
20-21	X	00000000h	Retired	
22	Х	0000h	Obsolete	
23-26	V	Varies	Firmware revision (8 ASCII characters)	
27-46	V	Varies	Model number (xxxxxxxxx)	
47	F	8010h	7:0- Maximum number of sectors transferred per	
			interrupt on MULTIPLE commands	
48	F	4000h	Trusted Computing feature set options(not support)	
49	F	2F00h	Capabilities	
50	F	4000h	Capabilities	
51-52	Х	000000000h	Obsolete	
53	F	0007h	Words 88 and 70:64 valid	
54	Х	*1	Obsolete	
55	Х	0010h	Obsolete	
56	Х	003Fh	Obsolete	
57-58	Х	*2	Obsolete	
59	F	5D10h	Sanitize and Number of sectors transferred per	
			interrupt on MULTIPLE commands	
60-61	V	*3	Maximum number of sector ( 28bit LBA mode)	
62	Х	0000h	Obsolete	
Word	F: Fixed	Default Value	Description	



	V: Variable		
	X:		
	retired/obsolete		
	/reserved		
63	F	0407h	Multi-word DMA modes supported/selected
64	F	0003h	PIO modes supported
65	F	0078h	Minimum Multiword DMA transfer cycle time per word
66	F	0078h	Manufacturer's recommended Multiword DMA transfer cycle time
67	F	0078h	Minimum PIO transfer cycle time without flow control
68	F	0078h	Minimum PIO transfer cycle time with IORDY flow control
69	F	1D00h	Additional Supported (support download microcode DMA)
70	Х	0000h	Reserved
71-74	Х	00000000000	Reserved for the IDENTIFY PACKET DEVICE command
		0000h	
75	F	001Fh	Queue depth
76	F	850Eh	Serial SATA capabilities
77	F	0006h	Serial ATA Additional Capabilities
78	F	004Ch	Serial ATA features supported
79	F	0040h	Serial ATA features enabled
80	F	0FF8h	Major Version Number
81	F	0000h	Minor Version Number
82	F	746Bh	Command set supported
83	F	7D01h	Command set supported
84	F	4163h	Command set/feature supported extension
85	F	7469h	Command set/feature enabled
86	F	BC01h	Command set/feature enabled
87	F	6163h	Command set/feature default
88	F	007Fh	Ultra DMA Modes
89	F	0003h	Time required for security erase unit completion
90	F	001Eh	Time required for Enhanced security erase completion
91	F	0000h	Current advanced power management value
92	F	FFFEh	Master Password Revision Code
93	F	0000h	Hardware reset result. For SATA devices, word 93 shall
			be set to the value 0000h.
Word	F: Fixed	Default Value	Description



	V: Variable		
	X:		
	retired/obsolete		
	/reserved		
94	X	0000h	Obsolete
95	F	0000h	Stream Minimum Request Size
96	F	0000h	Streaming Transfer Time – DMA
97	F	0000h	Streaming Access Latency – DMA and PIO
98-99	F	0000h	Streaming Performance Granularity
100-103	V	*4	Maximum user LBA for 48 bit Address feature set
104	F	0000h	Streaming Transfer Time – PIO
105	F	0008h	Maximum number of 512-byte blocks per DATA SET
			MANAGEMENT command
106	F	4000h	Physical sector size/Logical sector size
107	F	0000h	Inter-seek delay for ISO-7779 acoustic testing in
			microseconds
108-111	V	Varies	World Wide Name
112-115	Х	00000000000	Reserved
		0000h	
116	Х	0000h	Reserved
117-118	F	00000000h	Words per logical Sector
119	F	401Ch	Supported settings
120	F	401Ch	Command set/Feature Enabled/Supported
121-126	X	0h	Reserved
127	X	0000h	Obsolete
128	F	0021h	Security status
129-140	V	Varies	Vendor specific
141	V	Varies	Vendor specific
142-159	V	Varies	Vendor specific
160	X	000h	Reserved for CFA
161-167	X	0h	Reserved for CFA
168	V	Varies	Device Nominal Form Factor
169	F	0001h	DATA SET MANAGEMENT command is supported
170-173	F	000000000000	Additional Product Identifier
		000	
		0h	
174-175	Х	00000000h	Reserved
176-205	F	0h	Current media serial number



Word	F: Fixed V: Variable X: retired/obsolete /reserved	Default Value	Description
206	F	000h	SCT Command Transport
207-208	Х	00000000h	Reserved
209	F	4000h	Alignment of logical blocks within a physical block
210-211	F	00000000h	Write-Read-Verify Sector Count Mode 3 (not support)
212-213	F	00000000h	Write-Read-Verify Sector Count Mode 2 (not support)
214-216	X	0h	Obsolete
217	F	0001h	Non-rotating media device
218	X	000h	Reserved
219	X	0000h	NV Cache relate (not support)
220	V	0000h	Write read verify feature set current mode
221	X	0000h	Reserved
222	F	10FFh	Transport major version number
223	F	0000h	Transport minor version number
224-229	X	0h	Reserved
230-233	F	000000000000 0000h	Extend number of user addressable sectors
234	F	0001h	Minimum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h
235	F	FFFEh	Maximum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h
236-254	Х	0h	Reserved
255	F	XXA5h XX is variable	Integrity word (Checksum and Signature)

Table 6-3 List of Device Identification for Each Capacity

Capacity	*1	*2	*3	*4
(GB)	(Word 1/Word 54)	(Word 57 – 58)	(Word 60 – 61)	(Word 100 – 103)
32	3FFFh	FBFC10h	3BA2EB0h	3BA2EB0h
64	3FFFh	FBFC10h	7740AB0h	7740AB0h
120	3FFFh	FBFC10h	DF94BB0h	DF94BB0h
128	3FFFh	FBFC10h	EE7C2B0h	EE7C2B0h
240	3FFFh	FBFC10h	FFFFFFFh	1BF244B0h
256	3FFFh	FBFC10h	FFFFFFFh	1DCF32B0h
480	3FFFh	FBFC10h	FFFFFFFh	37E436B0h

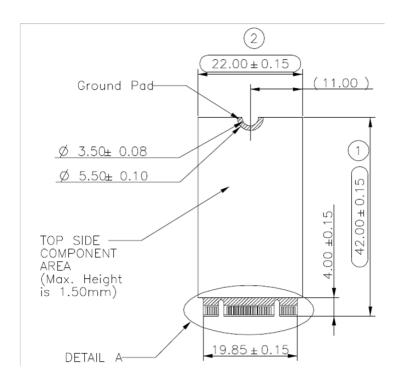


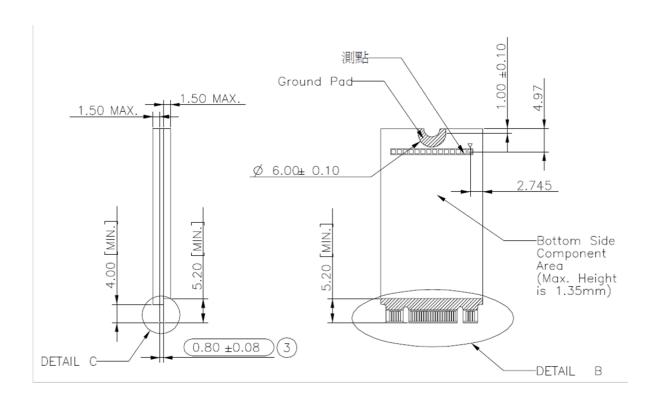
512	3FFFh	FBFC10h	FFFFFFFh	3B9E12B0h



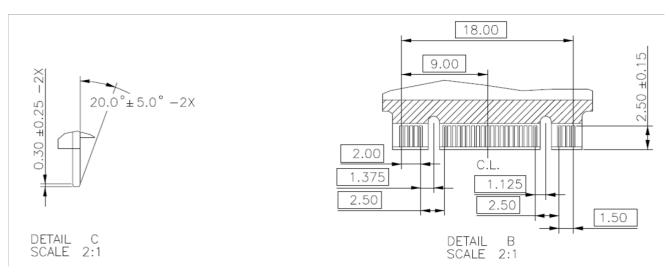
# 7. PHYSICAL DIMENSION

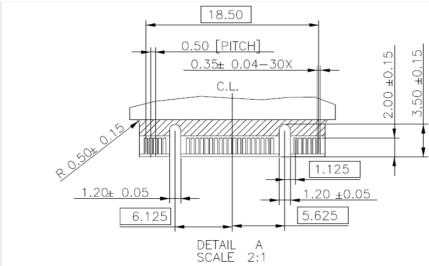
Dimension: 42mm (L) x 22mm (W) x 3.8mm (H)











## Notes:

- 1. = Max Component Height is
- 2. = No Component
- 3. Signal Copper/Print
- 4. General Tolerance :  $\pm 0.15$ mm
- 5. Check Point: 1 ~ 3



## 8. PRODUCT WARRANTY POLICY

In the event the Product does not conform to the specification within AAEON's agreed warranty period and such inconformity is solely attributable to AAEON's cause, AAEON agrees at its discretion replace or repair the nonconforming Product. Notwithstanding the foregoing, the aforementioned warranty shall exclude the inconformity arising from, in relation to or associated with:

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- (2) failure to comply with AAEON's instructions;
- (3) AAEON's compliance with customer (including customer's suppliers, subcontractors or downstream customers) indicated instructions, technologies, designs, specifications, materials, components, parts;
- (4) combination of the Product with other materials, components, parts, goods, hardware, firmware or software not developed by AAEON; or
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# 9. REFERENCE

The following table is to list out the standards that have been adopted for designing the product.

**Table 9-1 List of References** 

Title	Acronym/Source	
RoHS	Restriction of Hazardous Substances Directive; for further information,	
KOHS	please contact us at <a href="mailto:info@aaeon.eu">info@aaeon.eu</a> .	
M.2	http://www.pcisig.com	
Serial ATA Revision 3.2	http://www.sata-io.org	
ATA-8 spec	http://www.t13.org	
FCC: CISPR22	Federal Communications Commission; for further information, please	
PCC. CISPN22	contact us at <a href="mailto:info@aaeon.eu">info@aaeon.eu</a> .	
CE: EN55022	Consumer electronics certification; for further information, please	
CL. EN33022	contact us at info@aaeon.eu.	
	The Bureau of Standards, Metrology and Inspection; for further	
BSMI: 13438	information, please contact us at info@aaeon.eu.	



# **10. TERMINOLOGY**

The following table is to list out the acronyms that have been applied throughout the document.

**Table 10-1 List of Terminology** 

Term	Definitions
ATTO	Commercial performance benchmark application
DEVSLP	Device sleep mode
DIPM	Device initiated power management
HIPM	Host initiated power management
LBA	Logical block addressing
MB	Mega-byte
MTBF	Mean time between failures
NCQ	Native command queue
SATA	Serial advanced technology attachment
SDR	Synchronous dynamic access memory
S.M.A.R.T.	Self-monitoring, analysis and reporting technology
SSD	Solid state disk